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CLAIMS

WHAT IS CLAIMED IS:

- 1. A lithographic system for an integrated circuit fabrication process, the lithographic system comprising:
- 3 a computer; and
- a configurable mask or reticle coupled to the computer,
- 5 wherein the configurable mask or reticle allows light to be transmitted in a
- 6 pattern controlled by a control signal from the computer.
- 1 2. The lithographic system of claim 1, wherein the configurable 2 mask or reticle is an LCD or LED matrix.
 - 3. The lithographic system of claim 1 further comprising:
 a database for providing image information associated with a
 device to be patterned on a wafer, the computer using the image
 information to generate the control signal.
 - 4. The lithographic system of claim 3, wherein the database is stored on a storage media.
- 5. The lithographic system of claim 3, wherein the image information is related to transistor structures.
- 1 6. The lithographic system of claim 1, wherein the control 2 signal is a video signal.
- 7. A method of manufacturing an integrated circuit, the method comprising:

- providing a pattern of radiation via an LCD or LED assembly;
- 4 and
- 5 performing a semiconductor fabrication process in
- 6 accordance with the pattern of radiation.
- 1 8. The method of claim 7, further comprising:
- providing a second pattern of radiation via the LCD or LED
- 3 assembly; and
- 4 performing a second semiconductor fabrication process in
- 5 accordance with the second pattern of radiation.
- 9. The method of claim 7, wherein the pattern is provided to a
- wafer in a step and repeat process.
- 10. The method of claim 7, wherein the pattern is representative
- of a metal layer associated with the integrated circuit.
- 1 11. The method of claim 7, wherein the pattern is representative
- of a structure associated with a transistor for the integrated circuit.
- 1 12. The method of claim 7, wherein a representation of the
- 2 pattern is stored electronically.
- 1 13. The method of claim 7, wherein the integrated circuit is an
- 2 ASIC.
- 14. The method of claim 7, wherein the pattern is provided via
- the LCD assembly.
- 1 15. A pattern generator for an integrated circuit fabrication
- 2 system, the pattern generator comprising:

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- means for providing a pattern of light; and
 means for controlling the means for providing, wherein the
 means for controlling selects the pattern.
- 1 16. The pattern generator of claim 15, further comprising:
 2 means for providing a light through the means for providing a pattern.
- 1 The pattern generator of claim 16, further comprising:
 2 means for focusing the light on a wafer.
 - 18. The pattern generator of claim 15, further comprising:
 means for storing elements, wherein the means for
 controlling creates a control signal representative of the pattern in
 response to the elements.
 - 19. The pattern generator of claim 15, wherein the means for controlling includes a workstation executing a software program.
- 1 20. The pattern generator of claim 19, wherein the means for providing a pattern includes liquid crystals.